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6 The CIGS semiconductor detector for particle physics

7 **M. Togawa,** ^{a,b,1} **S. Fujii,** ^c **M. Imura,** ^d **K. Itabashi,** ^b **T. Isobe,** ^e **M. Miyahara,** ^{a,b} **J.**
8 **Nishinaga,** ^f **and H. Okumura** ^g

9 ^a*Institute of Particle and Nuclear Studies, High Energy Accelerator Research Organization (KEK), Tsukuba,*
10 *Ibaraki 305-0801, Japan.*

11 ^b*International Center for Quantum-field Measurement Systems for Studies of the Universe and Particles*
12 *(QUP, WPI), Tsukuba, Ibaraki 305-0801, Japan.*

13 ^c*The Graduate University for Advanced Studies, SOKENDAI, Kanagawa, Japan.*

14 ^d*Research Center for Functional Materials, National Institute for Material Science (NIMS), Tsukuba, Ibaraki*
15 *305-0044, Japan.*

16 ^e*Institute of Physical and Chemical Research (RIKEN), Wako, Saitama, 351-0198, Japan.*

17 ^f*Research Institute for Energy Conservation, National Institute of Advanced Industrial Science and Tech-*
18 *nology (AIST), Tsukuba, Ibaraki 305-8568, Japan.*

19 ^g*Faculty of Pure and Applied Sciences, University of Tsukuba, Tsukuba, Ibaraki 305-8573, Japan.*

20 *E-mail:* manabu.togawa@kek.jp

21 **ABSTRACT:** Silicon is commonly used as a sensor material in a wide variety of imaging application.
22 In recent high-energy and intensity beam experiments, high radiation tolerance is required, and
23 new semiconductor detector consisting of radiation-hard materials have been investigated. The
24 Cu(In,Ga)Se₂ (CIGS) semiconductor is expected to possess high radiation tolerance, with the ability
25 to recover from radiation damage through the compensation of defects by ions. The CIGS has
26 originally developed for a solar cell and its radiation tolerance was investigated for the usage in
27 space. The CIGS, featuring a recovery capability, would shed new light to particle detector in high
28 radiation environments. CIGS detectors (2 and 5 μm thick) were tested by Xe ion (400 MeV/u,
29 $^{132}\text{Xe}^{54+}$) at HIMAC, successfully detecting single Xe ion with a fast response. The output charge
30 is understandable through estimation with the GEANT4 simulation. With 0.6 MGy irradiation by
31 Xe ions, the CIGS output degraded to 50%, but it was recovered to 97% after the heat treatment
32 under 130 $^{\circ}\text{C}$ for 2 hours. This marks a significant step in confirming that CIGS semiconductors
33 can serve as particle detectors with recovery features for radiation damage.

34 **KEYWORDS:** Radiation-hard detectors, Radiation damage to detector materials (solid state), Mate-
35 rials for solid-state detectors

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¹Corresponding author

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45 1 Introduction

46 Silicon is commonly used as a sensor material in wide variety of imaging application. In recent
47 high energy and intensity beam experiments, high radiation tolerance is required. The semiconduc-
48 tor detectors, particularly those used in hadron colliders, receive the highest radiation in particle
49 physics experiments. These detectors, placed around the collision point to track particles, endure
50 damage from these collisions. The Large Hadron Collider (LHC), the world’s highest energy and
51 intensity proton collider, is planing a higher luminosity upgrade, with the radiation levels assum-
52 ing 10^{16} MeV n_{eq}/cm^2 and 7 MGy for Non Ionization Energy Loss (NIEL) and Total Ionization
53 Dose (TID), respectively. To withstand such high dose levels, detectors have been developed with
54 novel electrode structures, such as 3-D sensors, for example [1]. In anticipation of future hadron
55 collider experiments, the development of higher radiation-tolerant detectors with new innovations
56 is necessary.

57 A new semiconductor detector based on radiation hard material has been developed. Wide-gap
58 semiconductors, such as Diamond [2] and Gallium Nitride [3], has been investigated globally due
59 to their high binding energy among nucleons and low leakage current. The Cu(In,Ga)Se₂ (CIGS)
60 semiconductor is also expected to have high radiation tolerance coupled with a unique feature, re-
61 covery through the compensation of defects by ions. Originally developed for solar cells, CIGS’s
62 radiation tolerance was initially investigated for space applications [4]. As a preliminary experi-
63 ment, CIGS solar cells were irradiated with 10^{16} MeV n_{eq}/cm^2 and 7 MGy by 70 MeV proton beam
64 at the Cyclotron and Radioisotope Center (CYRIC), Tohoku University. The CIGS solar cells de-
65 teriorated after proton irradiation, with decreased conversion efficiency and short-circuit current
66 density. However, both parameters were gradually recovered through heat-light annealing [5].

67 This paper describes the demonstration of the world’s first CIGS detector, taking advantage of
68 its recovery feature for radiation hardness.”

69 2 The CIGS detector

70 The CIGS detector and its layer configuration are shown in Figure 1. The geometries of CIGS
71 detectors are approximately $5 \times 4 \text{ mm}^2$, and the thicknesses of active layer (CIGS layer) are 2 or 5
72 μm . CIGS is a p-type semiconductor and the CdS/ZnO is connected as n-type for the p-n junction.
73 In this detector, two n-type electrodes are prepared for signal read out. More details are described
74 in [5]. The depletion voltage is supplied from CIGS side with -2.0 V and the typical leakage current
75 is about 1 nA.

76 Since these new detectors have thin active layer, so far only 2 or 5 μm , the detection of single
77 charged particle is challenging due to very small charge outputs. A heavy ion beam is a better choice
78 to test such condition since charge outputs are expected to be large. Of course, the new detector would
79 be a good candidate as a heavy ion tracker, which also requires radiation tolerance. The expected
80 charge inducing by the penetration of a 400 MeV/u $^{132}\text{Xe}^{54+}$ beam on the 2 μm thick detector is
81 estimated by the GEANT4 simulation yielding a value of about 280 fC.

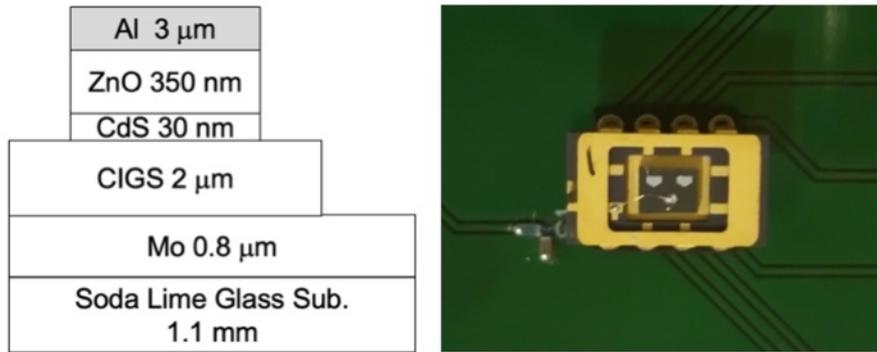


Figure 1. A CIGS detector configuration for 2 μm active thickness. Signals are read out from n-type CdS electrodes under home-base shaped Al pads for wirebonds.

82 3 Experimental Setup at HIMAC

83 For demonstration of the CIGS detector, a heavy ion beam, Xe ion (400 MeV/u, $^{132}\text{Xe}^{54+}$) at the
84 Heavy Ion Medical Accelerator in Chiba (HIMAC) was selected. We used the PH2 beam line, and
85 the experimental setup is shown in Figure 2. Only detectors were positioned on the beam axis, with
86 the readout circuits, including signal amplification, placed next to the detector. The beam size was
87 adjusted to approximately ϕ 3-5 mm using a fluorescent plate at the beginning. To induce irradiation
88 damage, the beam power was set to 10^7 particles per pulse (ppp) within 3.3-second pulse cycles.
89 The number of Xe beam was monitored by scintillator counter placed off-beam position.



Figure 2. A setup photo at the PH2 beam line. Only detectors were placed on the beam.

90 **4 Results**

91 **4.1 Signal output**

92 The outputs from the CIGS detector are shown in Figure 3. The data were recorded using the
93 waveform digitizing function in the readout ASIC, and the signal response looks sharp. The charge
94 generated by Xe ion penetration can be estimated by integrating the wave form signal (Integrated
95 ADC). The charge is approximately 180 fC and this value is 64% of the estimation by the GEANT4
96 simulation. Possible considerations are low charge collection efficiency and/or the excitation density
97 effect, but further investigations are needed for a conclusive understanding. We also irradiated the
98 5 μm thick CIGS detector and the output is about 2.5 times larger than that of 2 μm thick, as we
99 expected.

100 In Figure 4, the history of Integrated ADC value normalized to the value of un-irradiated are
101 plotted. The conditions were changed in five periods as followings,

102 (1) 0-16 h : Irradiation of Xe ion, 0.6 MGy in total : The output decreased to be 0.5,

103 (2) 18-20 h : Heat annealing with 130 $^{\circ}\text{C}$: The output recovered to be 0.97,

104 (3) 20-27 h : Irradiation of Xe ion, 0.2 MGy in total : The output decreased to be 0.8,

105 (4) 28-31 h : Heat annealing with 90 $^{\circ}\text{C}$: The output was not changed,

106 (5) 31-33 h : Heat annealing with 130 $^{\circ}\text{C}$: The output recovered to be 0.94.

107 It is confirmed the CIGS detector deteriorates in terms of signal output, likely due to the reduction
108 of charge collection efficiency by defects generated by irradiation. With heat annealing at 130 $^{\circ}\text{C}$,
109 the signal output almost returned to the initial value. The recovery shows no limits up to 0.8 MGy

110 and is repeatable. Since there was no significant recovery with 90 °C within this time period, the
 111 recovery appears to have strong temperature dependence between 90 and 130 °C.

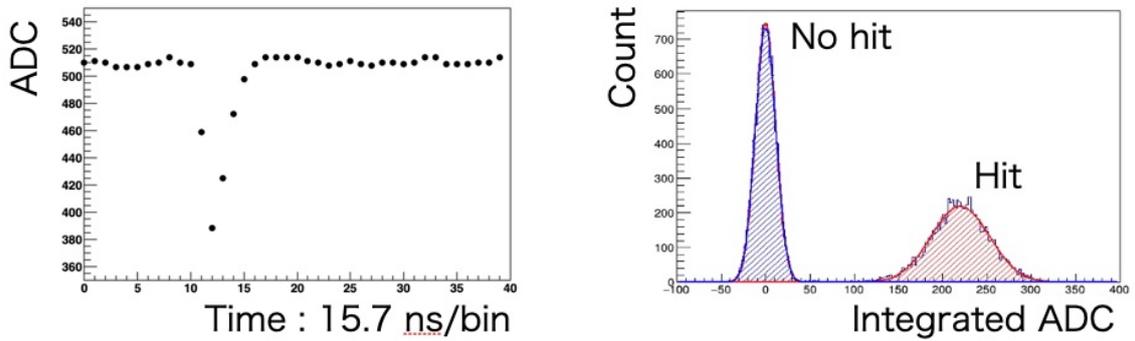


Figure 3. Left) Signal from single Xe ion event. The event is recorded by the wave form digitizing. Right) Integrated ADC values of recorded events. It is clearly separation of hit and no-hit.

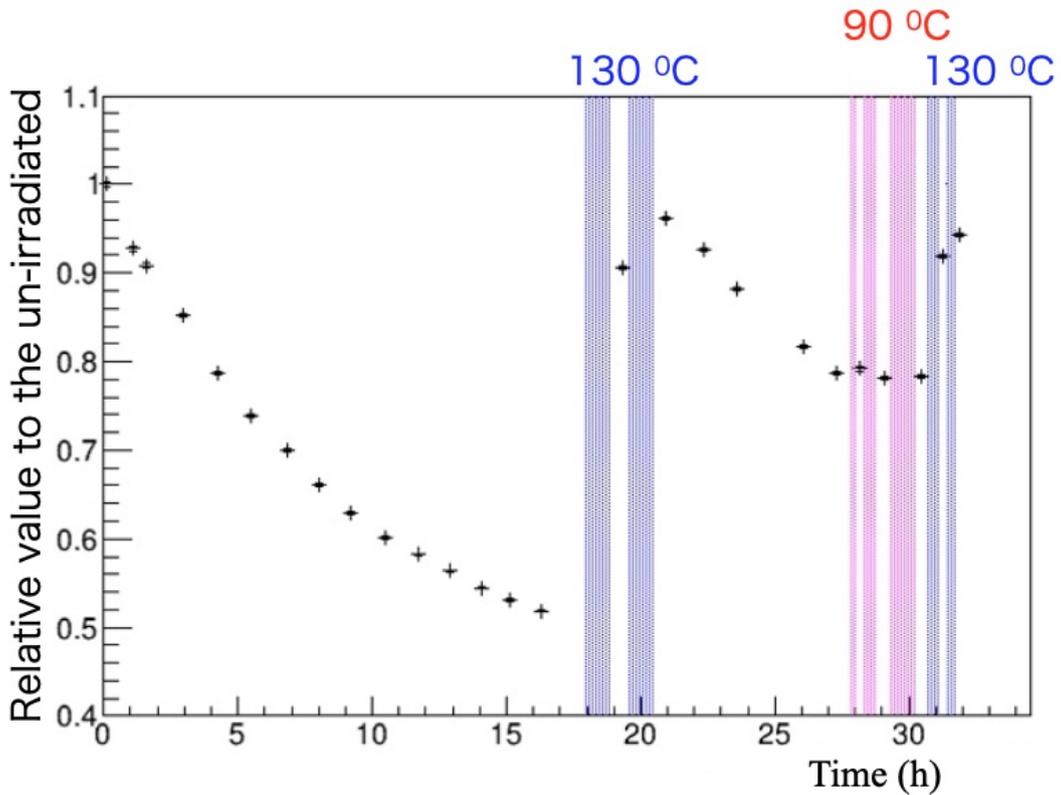


Figure 4. The output history of the CIGS detector.

112 4.2 Leakage current

113 The leakage current during 27-hour period, corresponding to periods of (1) to (3) in section 4.1, is
 114 shown in Figure 5. The leakage current increased proportionally to the amount of Xe irradiation

115 from 1 nA to 35 nA. After the heat annealing, the current returned to 3 nA, nearly reaching the
116 initial value. With additional Xe irradiation, the leakage current increased with same tendency in
117 period of (1).

118 Based on the results of signal output and leakage current, it can be inferred that recombination
119 centers generated by radiation damage are passivated by heat annealing.

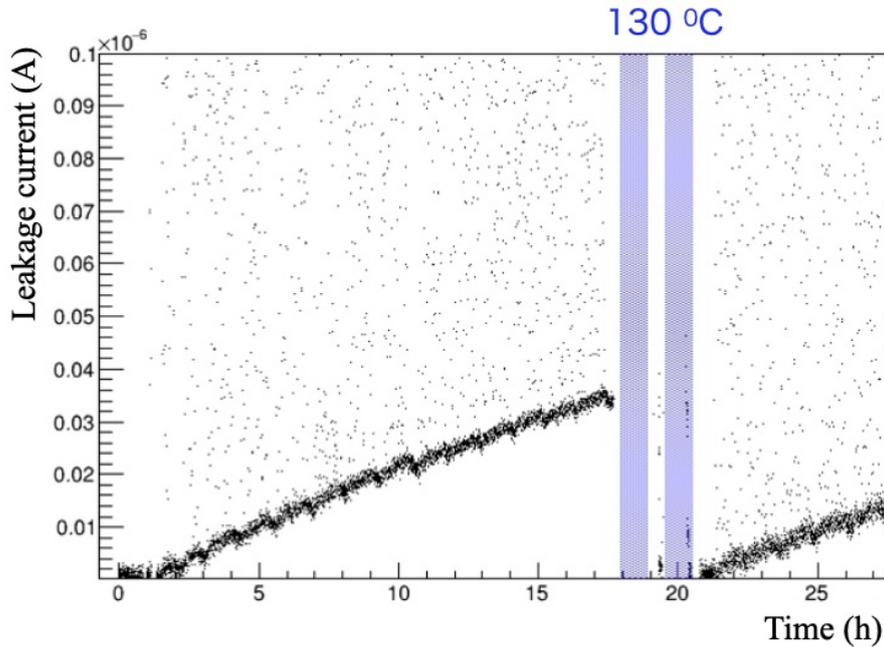


Figure 5. The leakage current history of the CIGS detector.

120 5 Conclusion

121 For the particle detector in a high radiation environment, we have developed new semiconductor
122 detectors using CIGS. The 2 μm thick detector was irradiated by Xe ions and it successfully detected
123 a single Xe ion particle with a fast response. For the accumulation of radiation damage, Xe beam was
124 irradiated up to 0.8 MGy. It has been confirmed that the decreased signal outputs can be recovered by
125 heat annealing at 130 $^{\circ}\text{C}$, and the recovery is repeatable. This marks a major milestone in realizing
126 the CIGS particle detector with a recovery mechanism. Since there was no significant recovery at 90
127 $^{\circ}\text{C}$ within this time period, the recovery appears to have a strong temperature dependence between
128 90 and 130 $^{\circ}\text{C}$.

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